Electron-Beam-Induced Phase Transition in the Transmission Electron Microscope: The Case of VO$_2$(B)

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Supplementary Information

List of contents.

Figure S1 | HRTEM image at the boundary of the VO$_2$(B)/VO$_2$(M1) interface of Fig. 3(c).
Figure S1 | HRTEM image at the boundary of the VO$_2$(B)/VO$_2$(M1) interface of Fig. 3(c). We have examined our samples by Transmission electron microscope (TEM) to confirm the sample structure at the boundary of the VO$_2$(B)/VO$_2$(M1) interface. The lattice image of VO$_2$(B) is depicted at the top and the vague image of the VO$_2$(M1) is shown at the bottom.